Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
09/974,554	LINDQVIST ET AL.
Examiner	Art Unit
Ellen C. Tran	2134

	SEARCHED		
Class	Subclass	Date	Examiner
713	162	1/5/2006	ECT

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARC		')
	DATE	EXMR
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	1/5/2006	ECT